

ECE/PHY 235: Introduction to Solid State Electronics, Fall 2024  
University of Wisconsin, Madison  
Homework #9, Instructor Ying Wang  
Due Sunday, Dec 15<sup>th</sup>, 11:59 PM, by electronic upload

PN junction IV curve

A silicon p-n junction diode is fabricated with the following parameters:  $N_A = 10^{16} \text{cm}^{-3}$ ,  $N_D = 10^{15} \text{cm}^{-3}$ . the intrinsic carrier concentration is  $n_i = 1.5 \times 10^{10} \text{cm}^{-3}$  at 300K. and the electron and hole mobility are  $\mu_n = 1350 \text{cm}^2/\text{V} \cdot \text{s}$ ,  $\mu_p = 480 \text{cm}^2/\text{V} \cdot \text{s}$  respectively. Junction across area is  $0.01 \text{cm}^2$ ; the electron lifetime in the p-region:  $\tau_n = 1 \mu\text{s}$ , the hole lifetime in the n-region:  $\tau_p = 2 \mu\text{s}$ .

- a) calculation the diffusion coefficient for electron and hole (based on Einstein relationship)
- b) calculate the building voltage across the depletion region.
- c) calculate the current at biases including: -0.1V, 0.3V and 0.7V

Please upload a write-up of your solution as a single PDF file. Name the file "Lastname\_HW9.pdf"